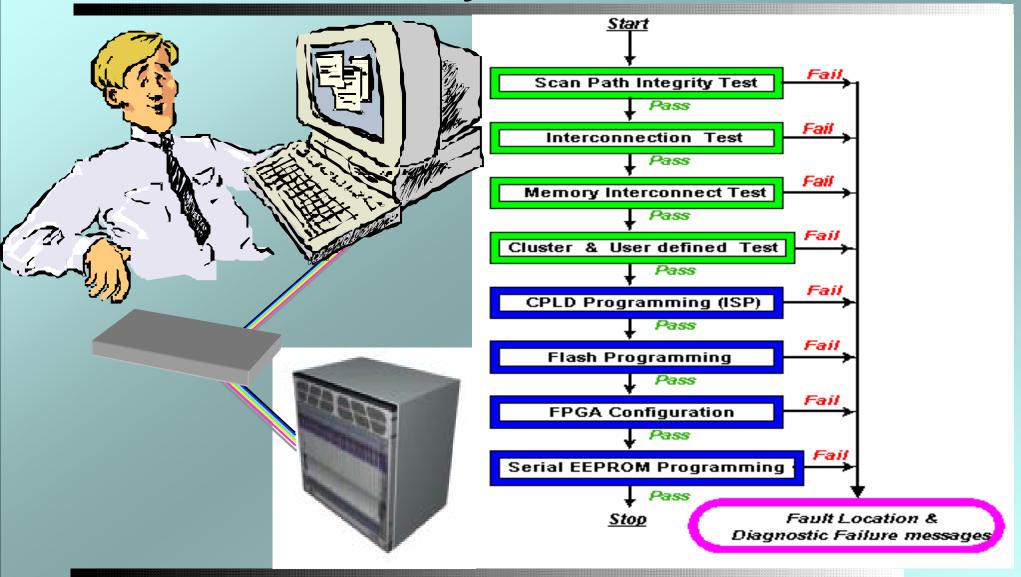


## 2.1 Activity Flowchart

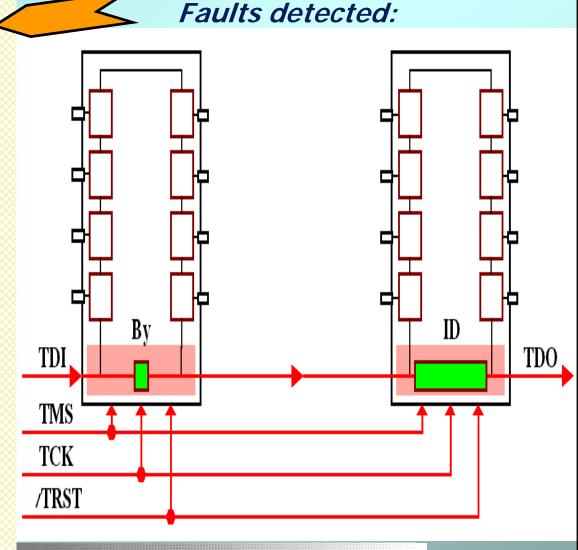




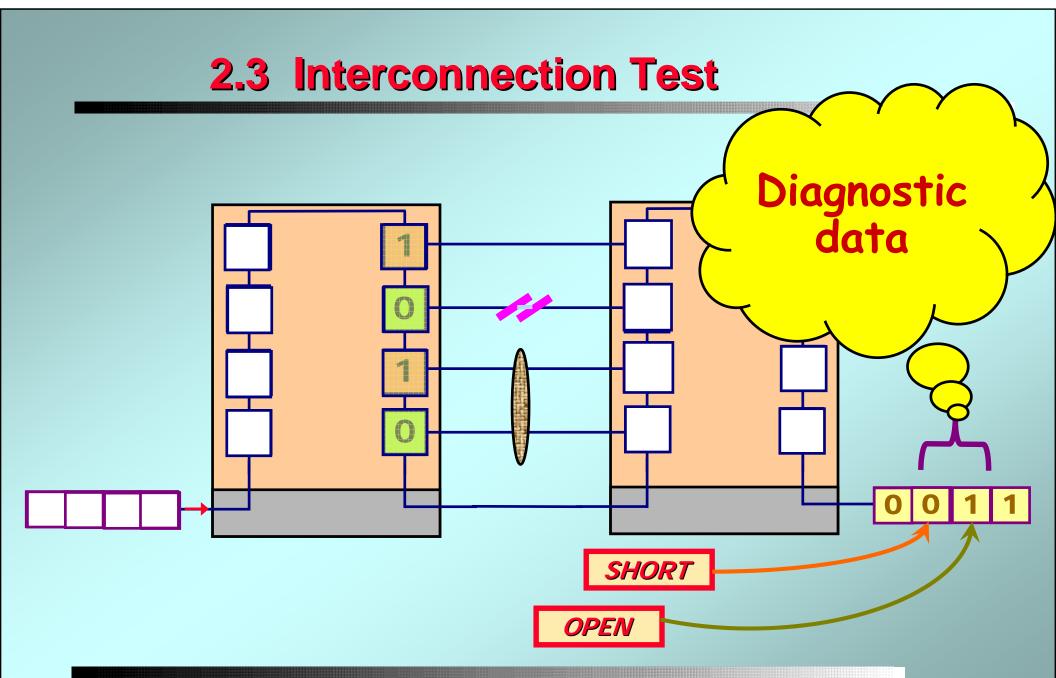


## 2.2 Scan Path Integrity Test

- S-a-0 on the TDI/TDO scan path
- ☐ Inoperative TCK
- Inoperative TMS
- ☐ Inoperative /TRST
- ☐ Incorrect scan path length (BS-register)or improper placement of BS devices
  - Instruction capture
  - BYPASS Instruction
  - ☐ IDCODE Instruction
  - ☐ USERCODE Instruction



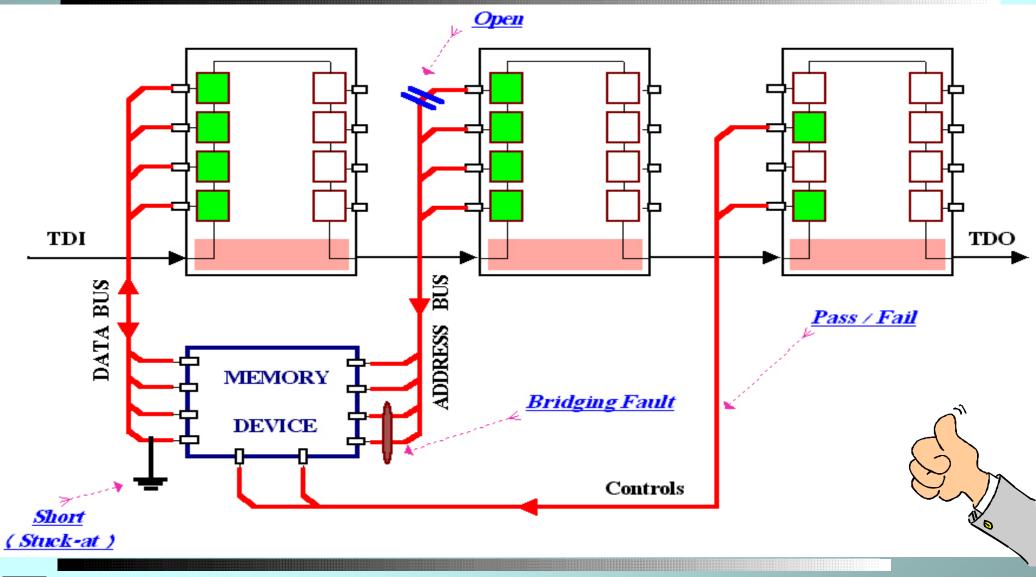
**Applications at the Board Level** 





2. Boundary-Scan Applications at the Board Level

## 2.4 Memory Interconnect Testing







2. Boundary-Scan Applications at the Board Level

## 2.5 On-Board Flash Programming

